	Application No.	Applicant(s)	
Notice of Allowability			AN
	10/623,247 Examiner	IKEDA ET AL. Art Unit	(10-0
	A.C. 1. D. Ot. C.	0077	
	Michael P. Stafira	2877	
The MAILING DATE of this communication app All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85 NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT F of the Office or upon petition by the applicant. See 37 CFR 1.31	S (OR REMAINS) CLOSED in i) or other appropriate commu RIGHTS. This application is s	this application. If not included inication will be mailed in due c	d ourse. THIS
1. X This communication is responsive to filing date 7/18/2003	<u>3</u> .		
2. ☑ The allowed claim(s) is/are <u>1-12</u> .		•	
 3.		or (f).	
2. Certified copies of the priority documents have		n No	
3. Copies of the certified copies of the priority de			on from the
International Bureau (PCT Rule 17.2(a)).			
* Certified copies not received:			
Applicant has THREE MONTHS FROM THE "MAILING DATE noted below. Failure to timely comply will result in ABANDON THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.	" of this communication to file MENT of this application.	a reply complying with the requ	uirements
4. A SUBSTITUTE OATH OR DECLARATION must be subtine INFORMAL PATENT APPLICATION (PTO-152) which gives	mitted. Note the attached EXA ves reason(s) why the oath or	AMINER'S AMENDMENT or NO declaration is deficient.	OTICE OF
5. CORRECTED DRAWINGS (as "replacement sheets") mu	ust be submitted.		
(a) I including changes required by the Notice of Draftspe	rson's Patent Drawing Reviev	v (PTO-948) attached	
1) 🗌 hereto or 2) 🔲 to Paper No./Mail Date			
(b) ☐ including changes required by the attached Examine Paper No./Mail Date			
Identifying indicia such as the application number (see 37 CFR each sheet. Replacement sheet(s) should be labeled as such in	1.84(c)) should be written on to the header according to 37 CF	ne drawings in the front (not the R 1.121(d).	back) of
 DEPOSIT OF and/or INFORMATION about the dep attached Examiner's comment regarding REQUIREMENT 	osit of BIOLOGICAL MATE TFOR THE DEPOSIT OF BIO	ERIAL must be submitted. N DLOGICAL MATERIAL.	ote the
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Attachment(s) 1. ☑ Notice of References Cited (PTO-892)	5. ☐ Notice of In	formal Patent Application (PTC)-152)
2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)		ummary (PTO-413),	
	Paper No.	/Mail Date Amendment/Comment	
 Information Disclosure Statements (PTO-1449 or PTO/SB Paper No./Mail Date 			
 Examiner's Comment Regarding Requirement for Deposit of Biological Material 	8. 🛛 Examiner's	Statement of Reasons for Allov	wance
C. Diological material	9. 🗌 Other	_·	
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DETAILED ACTION

Priority

1. Receipt is acknowledged of papers submitted under 35 U.S.C. 119(a)-(d), which papers have been placed of record in the file.

Allowable Subject Matter

- 2. Claims 1-12 are allowed over the prior art of record.
- 3. The following is an examiner's statement of reasons for allowance:

Regarding claim 1, the prior art fails to disclose or make obvious a particle size distribution device for measuring the size of particles by irradiating the particles in a carrier medium with radiation that can be diffracted and/or scattered by the particles and detected by a plurality of detectors having a concentration level adjusting unit for changing a relative amount of particles to an amount of carrier medium to be applied to the measurement cell; a storage device for storing the outputs of the detectors for each concentration level irradiated; a correction unit for providing a concentration correction constant; and a calculating unit for providing particle size distribution outputs from the outputs of the detectors as adjusted by the concentration correction constant, and in combination with the other recited limitations of claim 1. Claims 2-4 are allowed by the virtue of dependency on the allowed claim 1.

Regarding claim 5, the prior art fails to disclose or make obvious a particle size distribution device for measuring the size of particles by irradiating the particles in a carrier medium with radiation and detecting the influence of the particles on the radiation, the improvement of enabling a compensation for the amount of particles in the medium having a concentration level adjusting unit for changing a relative amount of particles to an amount of

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carrier medium to enable measurements of an influence of particles on the radiation that are substantially free from an effect relating to a level of concentration of particles to the carrier medium; and a correction unit for generating a proportional relationship between the amount of particles in the carrier medium and the output of the detectors, substantially free from an effect relating to the level of concentration of particles to the carrier medium, based on measurements form the concentration level adjustment unit to enable a calculation of concentration correction constants, and in combination with the other recited limitations of claim 5.

Regarding claim 6, the prior art fails to disclose or make obvious a method of correcting for concentration errors generated by particles in a carrier medium that are irradiated and measurements are taken by detectors having the steps of deriving a proportional relationship between the amount of particles in the carrier medium and an output of detectors in a concentration range substantially free from an effect relating to the level of concentration of particles to the carrier medium; extending the proportional relationship through concentration ranges that have an effect relating to the level of concentration of particles to the carrier medium; and determining concentration correction constants from a difference between the proportional relationship and detector outputs in the concentration ranges that have an effect relating to the level of concentration of particles to the carrier medium, and in combination with the other recited limitations of claim 6.

Regarding claim 7, the prior art fails to disclose or make obvious a particle diameter distribution measuring method for measuring the particle diameter distribution of a measuring sample, based on the detection values of plural detectors provided for detecting at predetermined angles diffracted light and/or scattered light generated when light is applied to the measuring

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sample having the steps of storing the output of the respective detectors at different concentrations of the measuring sample; determining concentration correction constants for correcting the detection values of the respective detectors at different concentrations of the sample; correcting detection values of the respective detectors by using the concentration correction constants, and determining the particle diameter distribution by using the corrected detection values of the respective detectors, and in combination with the other recited limitations of claim 7.

Regarding claim 8, the prior art fails to disclose or make obvious a particle diameter distribution measuring device for measuring particle diameter distribution of a measuring sample, based on the detection values of plural detectors provided for detecting at predetermined angles diffraction light and/or scattered light generated when light is applied to the measuring sample a storage part which stores the detection values of the detectors separately for each concentration of measuring sample and carrier fluid when the measuring sample is diluted to different concentrations; and an arithmetic processing part for generating concentration correction constants to remove an influence of error resulting from the concentration of the measuring sample separately for each detector by analyzing the detection values of the detectors stored in the storage part in association with the concentrations of the measuring sample, and in combination with the other recited limitations of claim 8.

Regarding claim 9, the prior art fails to disclose or make obvious a particle diameter distribution measuring device for measuring the particle diameter distribution of a measuring sample, based on the detection values of plural detectors provided for detecting at predetermined angles diffraction light and/or scattered light generated when light is applied to the measuring

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sample having a storage part which stores concentration correction constants obtained by finding the amount of correction in the detection values of the detectors in accordance with different concentrations of the measuring sample, based on the detection values of the detectors measured a plural number of times by changing the concentration of the measuring sample in a carrier fluid; and an arithmetic processing part which corrects the detection values of the detectors in accordance with the concentrations of the measuring sample by using the concentration correction constants, and then calculates the particle diameter distribution by using the corrected detection values, and in combination with the other recited limitations of claim 9.

Regarding claim 10, the prior art fails to disclose or make obvious a measuring program executed by a particle diameter distribution measuring device for measuring the particle diameter distribution of a measuring sample, based on the detection values of plural detectors provided for detecting at predetermined angles diffraction light and/or scattered light generated when light is applied to the measuring sample having measuring a measuring sample diluted to different concentrations and storing the detection values of the detectors separately for each concentration with a detection value grabbing program module; and analyzing the detection values of the detectors in association with the concentrations of the measuring samples and finding the concentration correction constants for each detector which removes the influence of error resulting from concentration with a correction constant generation program module, and in combination with the other recited limitations of claim 10. Claim 11 is allowed by the virtue of dependency on the allowed claim 10.

Regarding claim 12, the prior art fails to disclose or make obvious a measuring program executed by a particle diameter distribution measuring device for measuring the particle diameter

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distribution of a measuring sample, based on the detection values of plural detectors provided for detecting at predetermined angles diffraction light and/or scattered light generated when light is applied to the measuring sample having the steps of determining detection values of the respective detectors for different concentrations of the measuring sample to the carrier medium; determining concentration correction constants from the detection values; correcting the detection values with the concentration correction constants; and determining the particle diameter distribution from the correction detection values, and in combination with the other recited limitations of claim 12.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Michael P. Stafira whose telephone number is 571-272-2430. The examiner can normally be reached on 4/10 Schedule Mon.-Thurs..

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Gregory Toatley can be reached on 571-272-2800 ext. 77. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Michael P. Stafira Primary Examiner Art Unit 2877

September 20, 2005